

12500 TI Boulevard, MS 8640, Dallas, Texas 75243

PCN# 20180423002 Qualify New Assembly Material set for Selected Device(s) Change Notification / Sample Request

Date: May 09, 2018

To: PREMIER FARNELL PCN

Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

We request you acknowledge receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If you require samples or additional data to support your evaluation, please request within 30 days.

The proposed first ship date is indicated on page 3 of this notification, unless customer agreement has been reached on an earlier implementation of the change.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager (PCN www admin team@list.ti.com).

Sincerely,

PCN Team SC Business Services

20180423002 Attachment: 1

Products Affected:

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

DEVICE	CUSTOMER PART NUMBER
OPA564AIDWP	null
OPA564AIDWPR	null
OPA569AIDWP	null
OPA569AIDWPR	null
THS6012CDWP	null
TPA1517DWP	null
TPA6120A2DWP	null

Technical details of this Product Change follow on the next page(s).

PCN	Number:	201	.80423002					PCN Date:			ite:	May 9, 2018		
	Title: Qualify New Assembly Material set for Selected Device(s)													
Custo	omer Contact:	PCN I	<u>Manager</u>		Dept	: Q	uality Se							
Proposed 1 st Ship Date:			Aug. 9	Aug. 9, 2018				Estimated Sample Availability:			ple	Date provided sample reque		
Chan	ige Type:													
	Assembly Site				Design					١	Wafer Bu	mp Site		
	Assembly Process				Data Sh	neet				_		mp Material		
	Assembly Materials			Part number			change							
	Mechanical Specific			Test Site						_	Wafer Fab Site			
F	Packing/Shipping/L	_abel	ing	Test Process			5		Щ	_	Wafer Fab Materials			
										1	Wafer Fab Process			
					PCN	Det	ails							
Desc	ription of Change	e:												
devic	s Instruments is places listed in "Productions part changes	ct af	fected"	sec	tion belo				ema	air	n in curre		cility	
	Material		<u> </u>		urrent						oposed			
	Mount Compoun	<u>d</u>	404		4, 42062	201					208458			
	Mold Compound		<u> </u>		205443						211649			
	Lead finish		Sta	<u>anda</u>	ard NiPdA	۹u	Roug	Roughened NiPdAu (Single side)						
	on for Change:													
Conti	nuity of supply.													
Antic	cipated impact or	n Fit	, Form	, Fι	ınction,	Qua	ity or R	elia	bili	ity	/ (positiv	ve / negative) :	
None														
Antic	cipated impact or	n Ma	terial	Dec	laration									
	No Impact to the		⊠ Ma	ater	ial Declar	ratior	ns or Pro	duct	: Cc	ont	tent repo	rts are driven f	rom	
	Material Declaration	on				a and will be available following the production								
						production release the revised reports can be								
						the <u>TI Eco-Info website</u> . There is no impact to the								
						ng current regulatory compliance requirements								
	with this PCN change.													
Changes to product identification resulting from this PCN:														
None.														
Prod	uct Affected:													
DBV	401AIDWP	ΩP	Δ569ΔII	אַר	DG4	THS	6012CD	N/DD)		TDΔ61	20A2DWP		
	DRV401AIDWP OPA569AIDWPG4 DRV401AIDWPG4 OPA569AIDWPR										20A2DWPG4			
		SN0301043DWP				THS6012IDWP				+				
	DRV401AIDWPR SN0301043DWP DRV401AIDWPRG4 SN0301043DWPR			THS6012IDWPR TPA6120A2DWF			20A2DWPR 20A2DWPRG4	+						
						S6032CDWP								
HPA00892DWPR THS6002CDWP OPA564AIDWD THS6002CDWPG4				HS6032IDWP TPPM0110DWP				\dashv						
	.564AIDWD .564AIDWDR		THS6002CDWPG4					6032IDWPR TPPM0110DWP				\dashv		
	.564AIDWDR .564AIDWP		HS6002IDWP				1517DWP TPPM0111DWP 1517DWPG4			TITONAL	+			
	.564AIDWPR		HS6002IDWPR HS6012CDWP				1517DW 1517DW						-	
	.569AIDWP		S6012C				1517DW 1517DW		1				+	
	JOSKID AAL	1 1113	ンロロエムに	レ٧٧	1 0 7	IIFA	エンエノレ۷۷	ı NO	-		1		1	

Qualification Report

HSOIC G700LB + FS849 Enterprise Qualification in TITL

Approve Date 11-Apr-2018

Product Attributes

Attributes	Qual Device: <u>DRV401AIDWPR</u>	QBS Package Reference: TPS653853QDCARQ1
Assembly Site	TAI	TAI
Package Family	HSOIC	HTSSOP
Flammability Rating	UL 94 V-0	UL 94 V-0
Wafer Fab Supplier	DMO5S	RFAB/DMOS6 (MFF)
Wafer Fab Process	50HPA07	LBC8

⁻ QBS: Qual By Similarity

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Data Displayed as: Number of lots / Total sample size / Total failed						
Туре	Test Name / Condition	Duration	Qual Device: DRV401AIDWPR	QBS Package Reference: <u>TPS653853QDCARQ1</u>		
AC	Autoclave 121C	96 Hours	3/231/0	3/231/0		
CDM	ESD - CDM - Q100	1000 V corner pins only	-	1/3/0		
CDM	ESD - CDM - Q100	750 V (all pins)	-	1/3/0		
ED	Auto Electrical Distributions	Cpk>1.67 Room, hot, and cold test	-	1/90/0		
ELFR	Early Life Failure Rate, 125C	48 Hours	-	3/2400/0		
ELFR	Early Life Failure Rate, 150C	48 Hours	-	1/805/0		
HAST	Biased HAST, 130C/85%RH	192 Hours (for information)	-	3/231/0		
HAST	Biased HAST, 130C/85%RH	96 Hours	-	3/231/0		
HBM	ESD - HBM - Q100	2000 V	-	1/3/0		
HTOL	Life Test, 125C	1000 Hours	-	3/231/0		
HTSL	High Temp Storage Bake 150C	1000 Hours	-	3/231/0		
HTSL	High Temp Storage Bake 170C	420 Hours	3/231/0	-		
LI	Lead Integrity	Leads	3/135/0	-		
LI	Lead Pull	Leads	3/135/0	-		
LU	Latch-up	(per JESD78)	-	1/6/0		
MQ	Manufacturability (Assembly)	(per mfg. Site specification)	Pass	-		
MQ	Manufacturability (Auto Assembly)	(per automotive requirements)	-	Pass		
PD	Physical Dimension	-	3/90/0	-		
PTC	Power Temperature Cycle, - 40/125C	1000 cycles	-	1/47/0		
SD	Surface Mount Solderability	>95% Lead Coverage	3/66/0	-		
TC	Temperature Cycle, -65/150C	500 Cycles	3/231/0	3/231/0		
TC	Temperature Cycle, -65/150C	1000 Cycles	-	3/231/0		
WBP	Post Temp. Cycle Bond Pull	500 Cycles	-	3/15/0		
WBP	Bond Pull	Wires	3/228/0	-		
WBS	Ball Bond Shear	Wires	3/228/0	-		

⁻ Qual Device DRV401AIDWPR is qualified at LEVEL2-260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles Quality and Environmental data is available at Tl's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

THIS INFORMATION RELATING TO QUALITY AND RELIABILITY IS PROVIDED "AS IS." Product information detailed in this report may not accurately reflect TI's current product materials, processes and testing used in the construction of the TI products. Customers are solely responsible to conduct sufficient engineering and additional qualification testing to determine whether a device is suitable for use in their applications. Using TI products outside limits stated in TI's datasheet may void TI's warranty. See TI's Terms of Sale at "http://www.ti.com/lsds/ti/legal/termsofsale.page"

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com